

# TRANSPORT AND NON EQUILIBRIUM BEHAVIOUR IN SEMICONDUCTORS.

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## Carrier transport phenomena

### Carrier drift

$$J_{\text{drf}} = \rho v_d$$

$\rho$  is the charge density,  $v_d$  the drift current

$$J_{p|\text{drf}} = (ep)v_{dp}$$

$v_p$  is the average drift velocity of holes, and  $J_{p|\text{drf}}$  the drift current density due to holes.

$$F = m_{cp}^* a = m_{cp}^* \frac{dv}{dt} = eE$$

is the equation of motion  $e$  is the magnitude of the electron charge  $E$  the electric field and  $m_{cp}^*$  the effective mass  $a$  the acceleration

$$v_{dp} = \mu_p$$

$\mu_p$  is the hole mobility

$$J_{p|\text{drf}} = e\mu_p p E$$

In total:

$$J_{\text{drf}} = e(\mu_n n + \mu_p p) E$$

$v$  is the velocity due to the electric field:

$$v = \frac{eEt}{m_{cp}^*}$$

Now let the time between collisions be  $\tau_{cp}$

$$\langle v_d \rangle = \frac{1}{2} \frac{eE\tau_{cp}}{m_{cp}^*}$$

$$\mu_p = \frac{v_{dp}}{E} = \frac{e\tau_{cp}}{m_{cp}^*}$$

There are two types of scattering, lattice and ionized:

$$\mu_L \propto T^{-3/2}$$

$$\mu_I \propto \frac{T^{3/2}}{N_I}$$

$$\frac{dt}{\tau} = \frac{dt}{\tau_I} + \frac{dt}{\tau_L}$$

$$\frac{1}{\mu} = \frac{1}{\mu_I} + \frac{1}{\mu_L}$$

$$J_{\text{drf}} = e(\mu_n n + \mu_p p) E = \sigma E = \frac{1}{\rho} E$$

$$J = \frac{I}{A} \quad E = \frac{V}{L}$$

$$\frac{I}{A} = \sigma \frac{V}{L}$$

$$V = \frac{L}{\sigma A} I = \frac{\rho L}{A} I = IR$$

ohms law. now think p-tpe such that  $N_a \gg n_i$

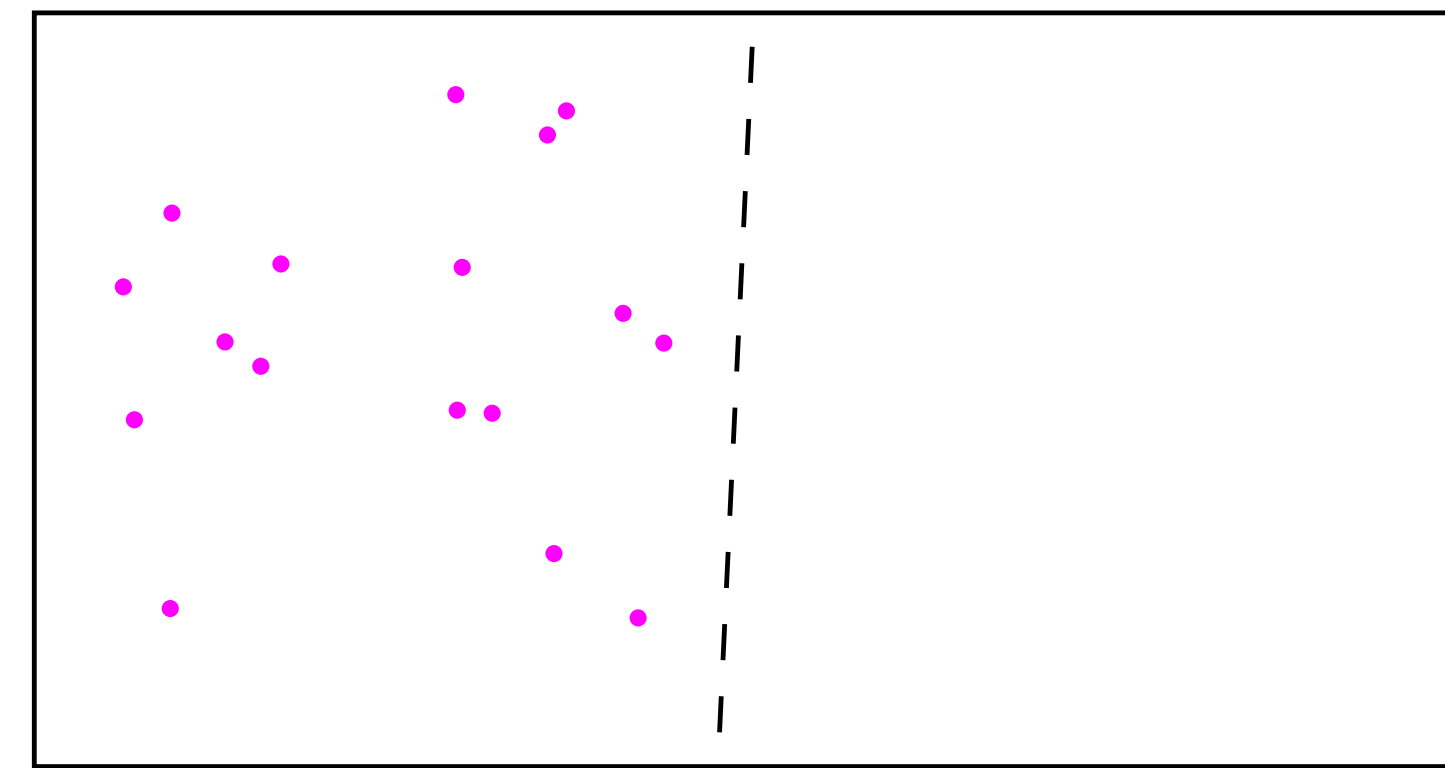
$$\sigma = e(\mu_n n + \mu_p p) \approx e\mu_p p \approx \frac{1}{\rho}$$

For an intrinsic material

$$\sigma = e(\mu_n + \mu_p) n_i$$

$$v_n = \frac{v_s}{\sqrt{1 + \left(\frac{E_{on}}{E}\right)^2}} \approx \left(\frac{E}{E_{on}}\right) v_s$$

### Carrier diffusion



$$x = 0$$

$$F_n = \frac{1}{2} n(-l) v_{th} - \frac{1}{2} n(+l) v_{th} = \frac{1}{2} v_{th} [n(-l) - n(+l)]$$

Taylor expansion

$$F_n = \frac{1}{2} v_{th} \left( \left[ n(0) - \frac{dn}{dx} \right] - \left[ n(0) + l \frac{dn}{dx} \right] \right) \\ = -v_{th} l \frac{dn}{dx}$$

$$J = -eF_n = +e v_{th} l \frac{dn}{dx}$$

$$J_{nx|\text{dif}} = e D_n \frac{dn}{dx}$$

$$J_{px|\text{dif}} = -e D_p \frac{dp}{dx}$$

The total current is then

$$J = en\mu_n E_x + ep\mu_p E_x + e D_n \frac{dn}{dx} - e D_p \frac{dp}{dx}$$

$$J = en\mu_n E + ep\mu_p E + e D_n \nabla n - e D_p \nabla p$$

### Graded impurity distribution

$$\phi = \frac{1}{e} (E_F - E_{Fi})$$

$$E_x = -\frac{d\phi}{dx} = \frac{1}{e} \frac{dE_{Fi}}{dx}$$

assuming quasi neutrality

$$n_0 = n_i \exp \left[ \frac{E_F - E_{Fi}}{kT} \right] \approx N_d(x)$$

$$E_F - E_{Fi} = kT \ln \left( \frac{N_d(x)}{n_i} \right)$$

$$-\frac{dE_{Fi}}{dx} = \frac{kT}{N_d(x)} \frac{dN_d(x)}{dx}$$

$$E_x = -\frac{kT}{e} \frac{1}{N_d(x)} \frac{dN_d(x)}{dx}$$

no electrical connection and thermal equilibrium:

$$J_n = 0 = en\mu_n E_x + e D_n \frac{dn}{dx}$$

assume quasi-neutrality ( $n \approx N_d(x)$ )

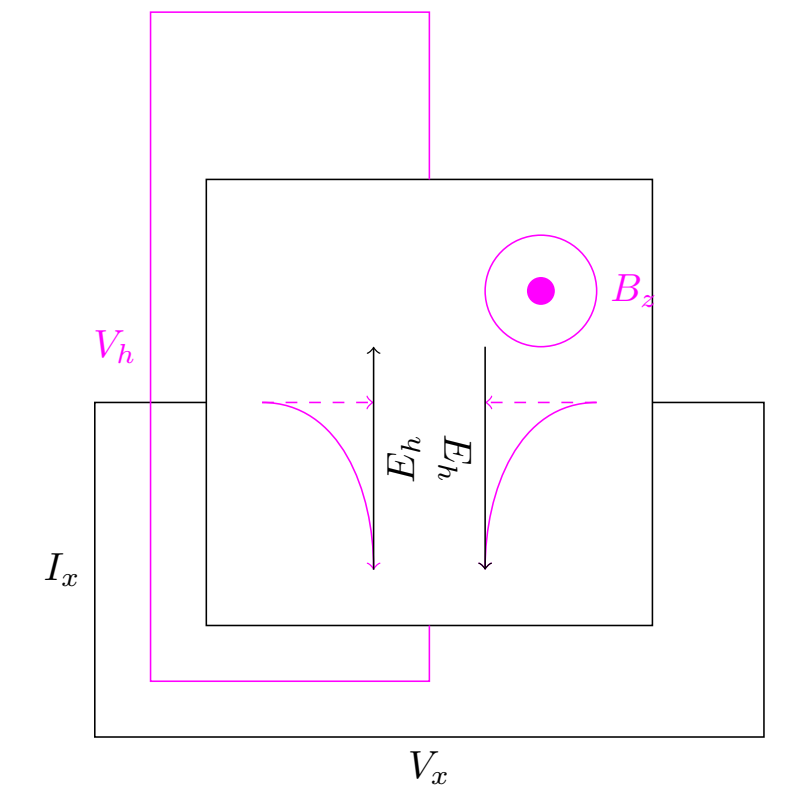
$$= e N_d(x) \mu_n E_x + e D_n \frac{dN_d(x)}{dx}$$

$$= -e \mu_n N_d(x) \frac{kT}{e} \frac{1}{N_d(x)} \frac{dN_d(x)}{dx} + e D_n \frac{dN_d(x)}{dx}$$

this needs the conditions (known as the Einstein relations

$$\frac{D_n}{\mu_n} = \frac{D_p}{\mu_p} = \frac{kT}{e}$$

### The Hall effect



$$F = qv \times B$$

As the holes and electrons move in the same direction the important thing is whether there's an excess of one or the other. That's the case in an p or n type semiconductor. An electric field will then be made to compensate for this field:

$$F = q[E + v \times B] = 0$$

$$qE_y = qv_x B_z$$

$$v_H = v_x W B_z$$

$$v_{dx} = \frac{J_x}{ep} = \frac{I_x}{epWd}$$

$$v_H = \frac{I_x B_z}{epd}$$

$$p = \frac{I_x B_z}{edV_H}$$

$$v_H = \frac{I_x B_z}{end}$$

$$n = -\frac{I_x B_z}{edV_H}$$

$$J_x = ep\mu_p E_x$$

$$\frac{I_x}{Wd} = \frac{ep\mu_p V_x}{L}$$

$$\mu_p = \frac{L}{epV_x Wd}$$

$$\mu_n = \frac{L}{enV_x Wd}$$

In the above  $L$  is the length of the semiconductor in the direction of the current,  $W$  is the width of the semiconductor in the direction of neither the current nor the magnetic field,  $d$  is the thickness of the semiconductor in the direction of the magnetic field.